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INTRODUCTION

CeO₂ is an oxide with variable chemical properties due to the external band structure, influenced by the f-orbitals of the rare earth metal Cerium.

We found multiple bias induced processes in oxide ceria thin films grown on different substrates by Pulsed Laser Deposition. Our measurements showed the formation of irreversible deformations on the oxide surface, as a consequence of the bias applied to the AFM tip. The exchange of electrons between tip and sample plays a pivotal role in the explanation of the electrochemical process.

The expansion of 7% of the total thickness is found to be compatible with ceria surface reduction, formation of oxygen vacancies and water physical adsorption.

Under reducing conditions, CeO₂ loses a fraction of oxygen ions, leaving oxygen vacancies, and becoming CeO_{2-δ}. In the latter, the oxidation state of Cerium changes from +4 to +3.

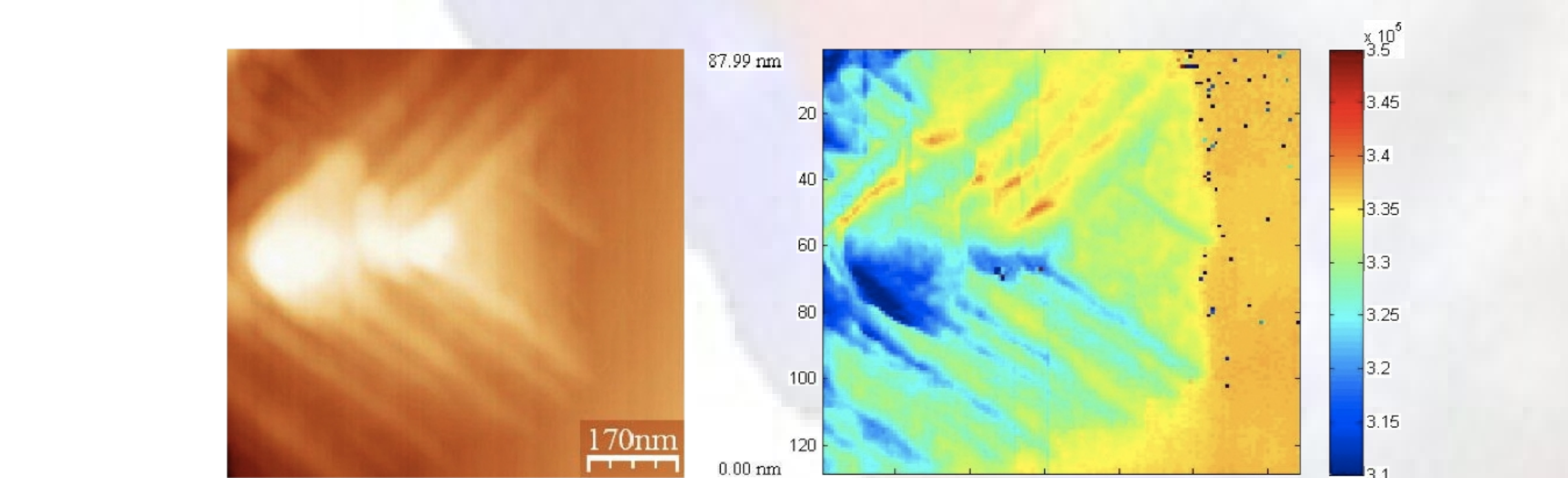
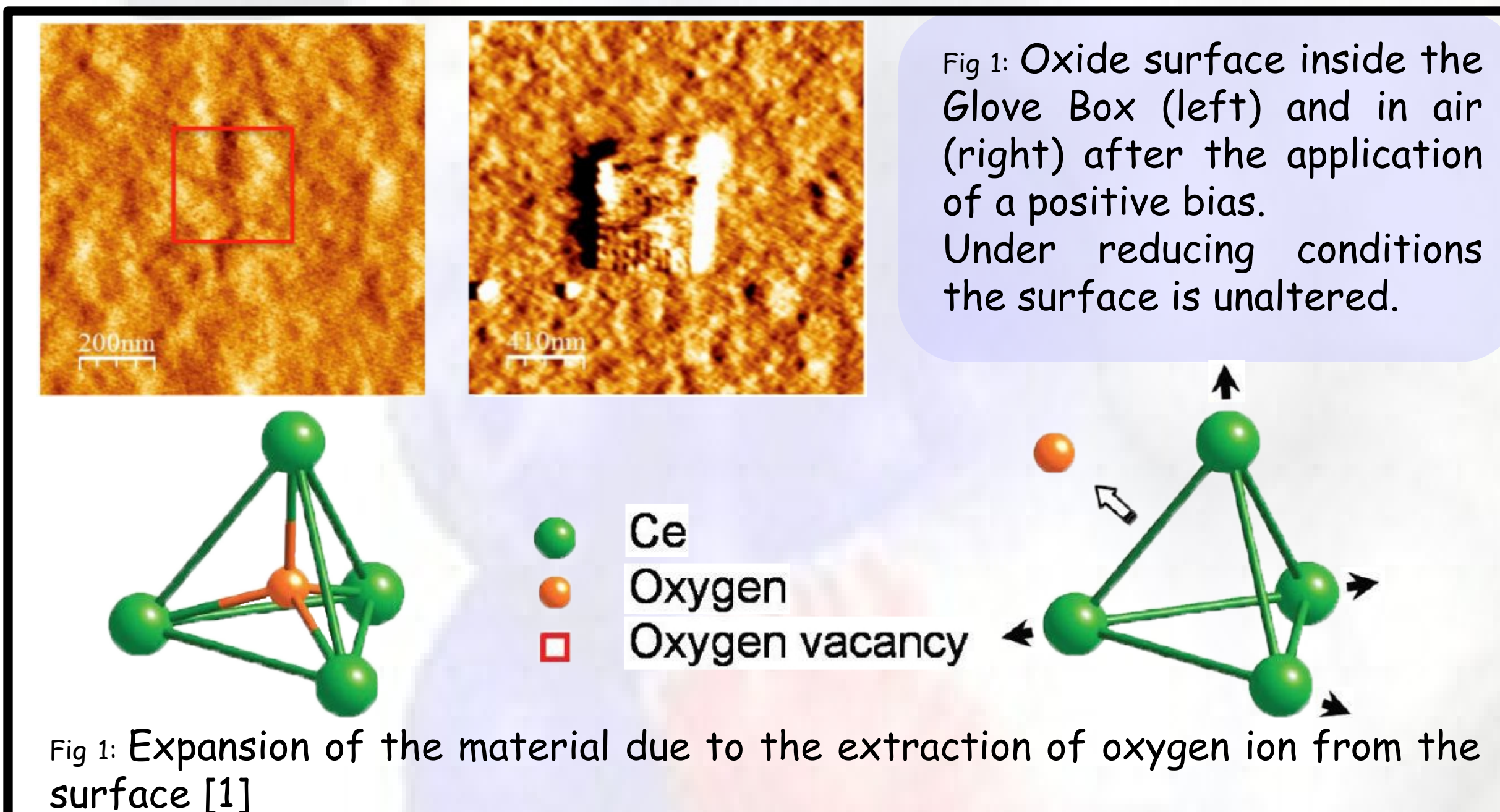
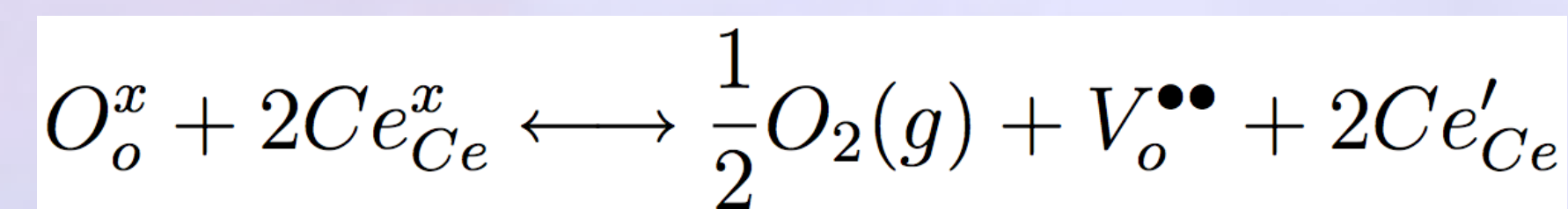
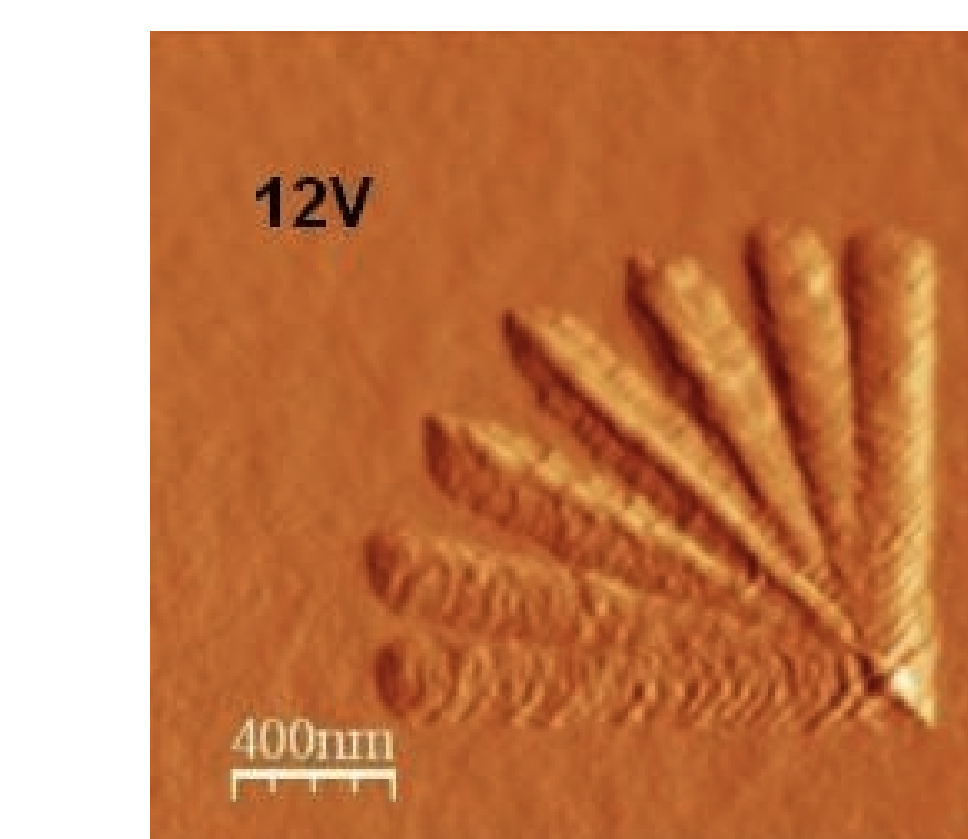
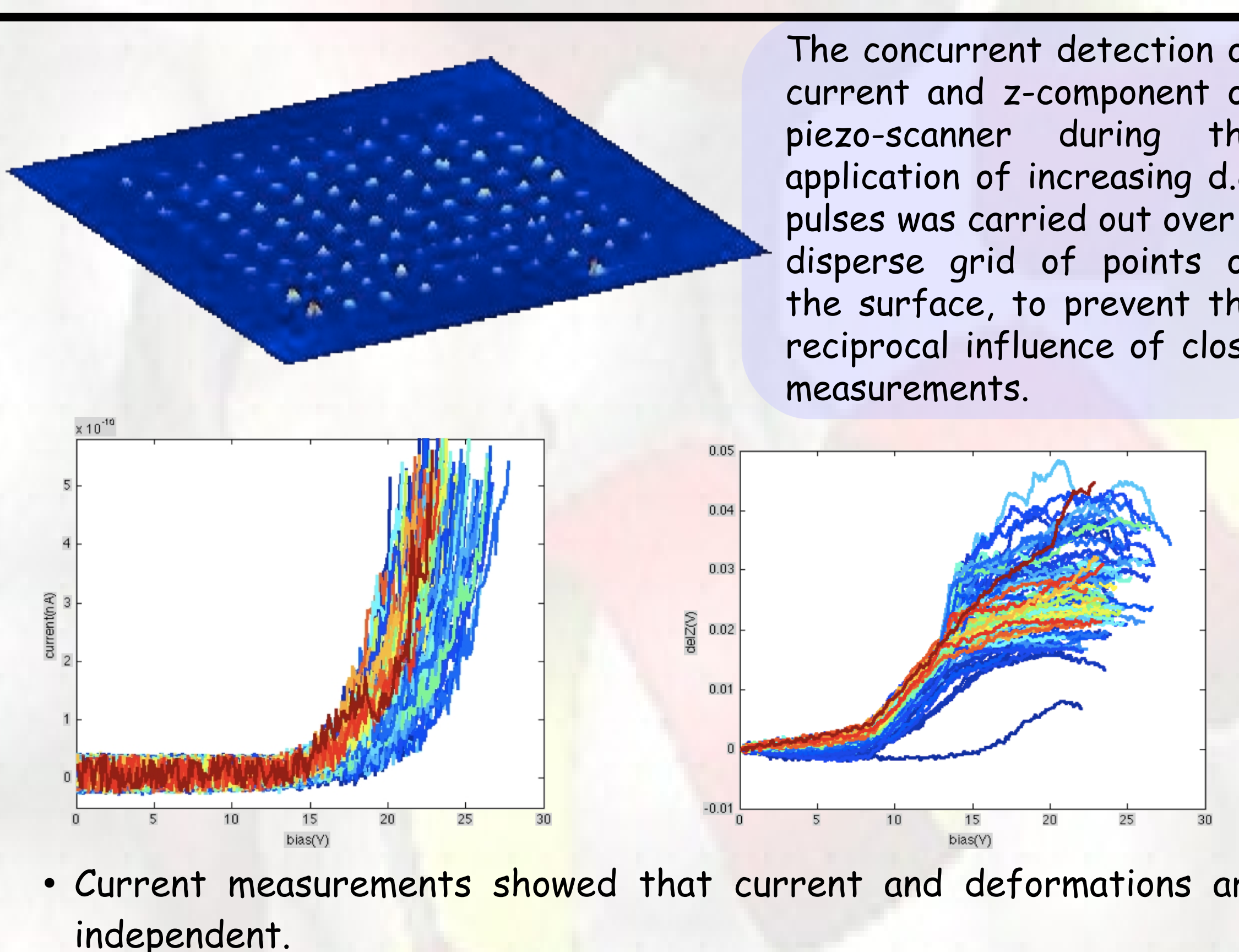
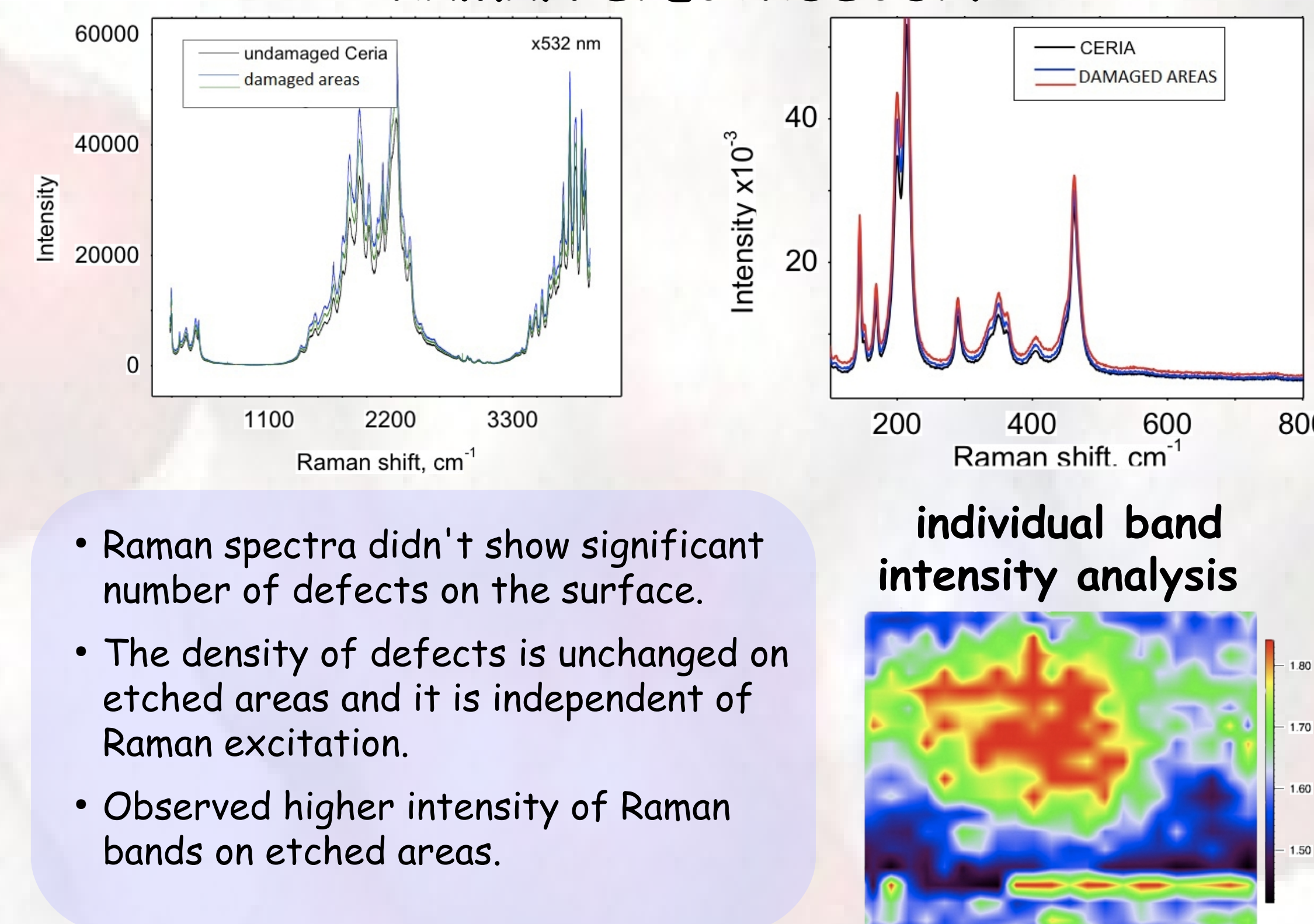


Fig 2: being the resonant frequency closely related with the tip-sample interaction through the spring constant and the reduced mass of the system in Hooke's approximation, the decrease of the resonant frequency is compatible with the decrease of the density surface sample after the induced bias process occurs. This can be explained by considering the extraction of oxygen ions from the lattice, leaving vacancies behind.



The electrochemical writing occurs for positive bias between + 5 V and + 41 V, and for negative bias, in the range between -26 V and -35 V. The lateral dimensions of the deformations exceed considerably the tip-surface contact area.

RAMAN SPECTROSCOPY



TEMPERATURE CONTROL

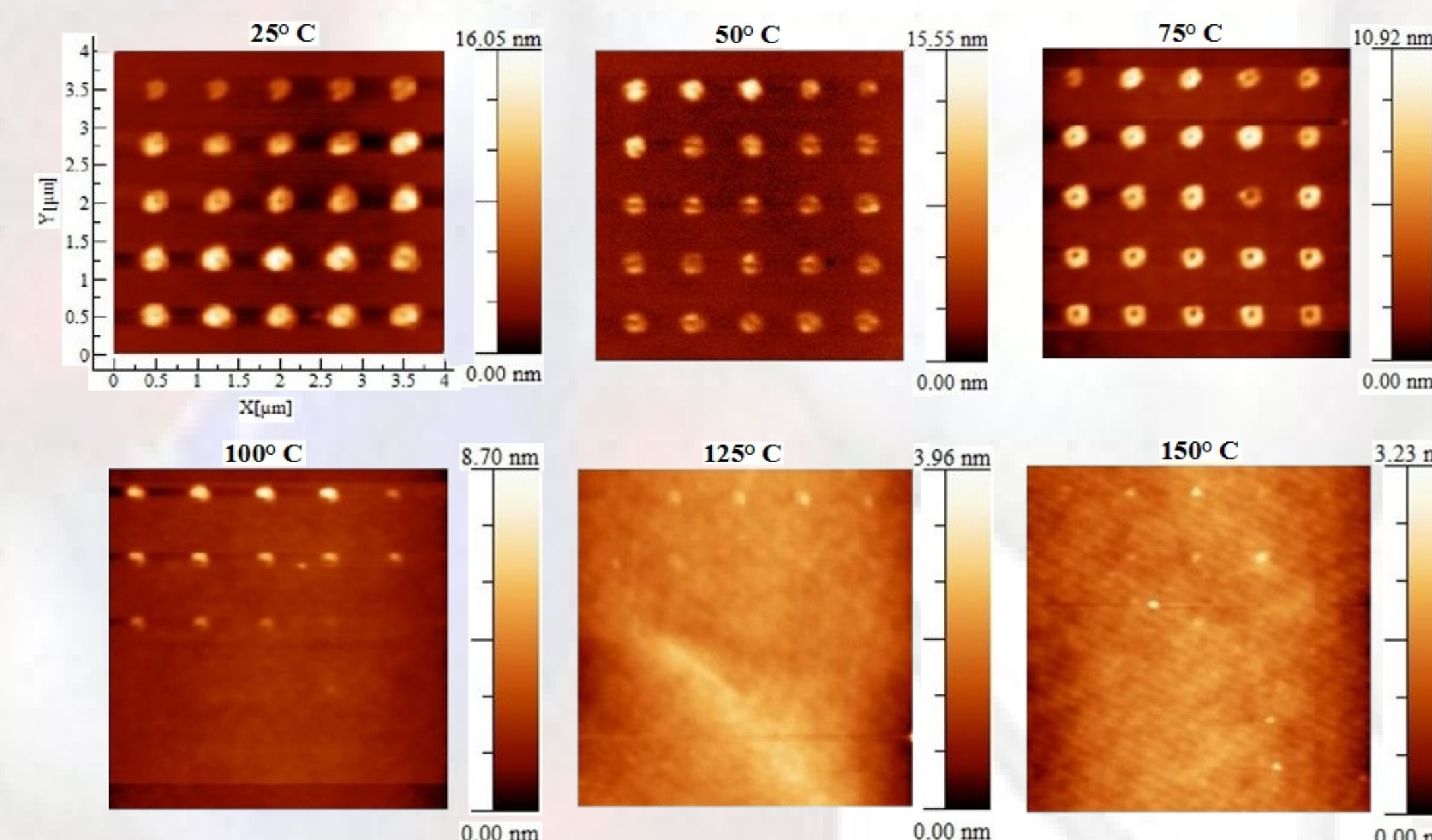


Fig 3: Over 100°C the number and size of particles decrease considerably. This result demonstrates the fundamental role of water in the electrochemical process. In dry atmosphere conditions the poor tip-sample contact doesn't allow any change in Ceria-Oxygen bonds. In elevated humidity the presence of water droplet at the junction facilitate electrochemically-driven oxygen vacancies formation.

ELECTROCHEMICAL STRAIN MICROSCOPY

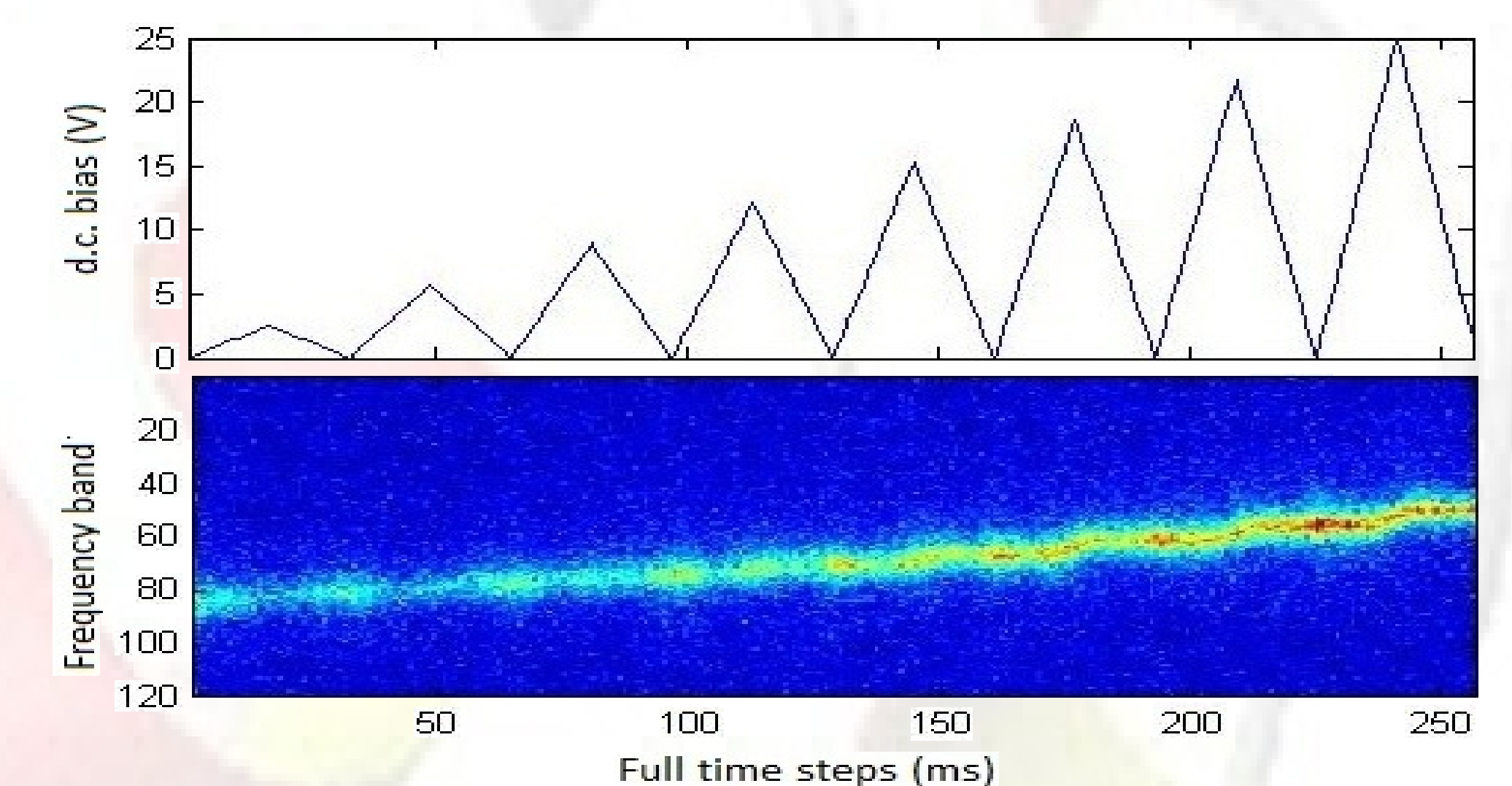
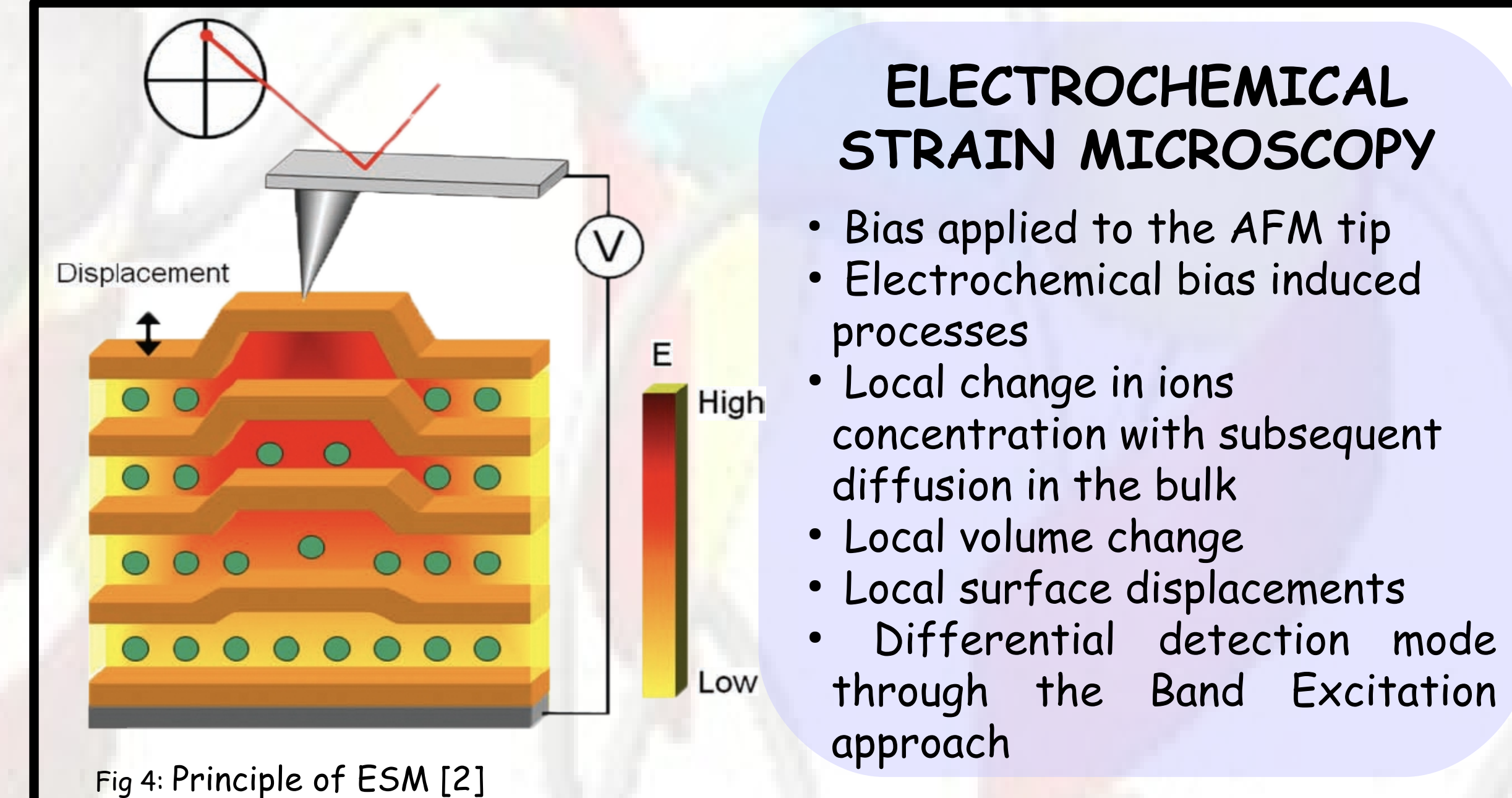
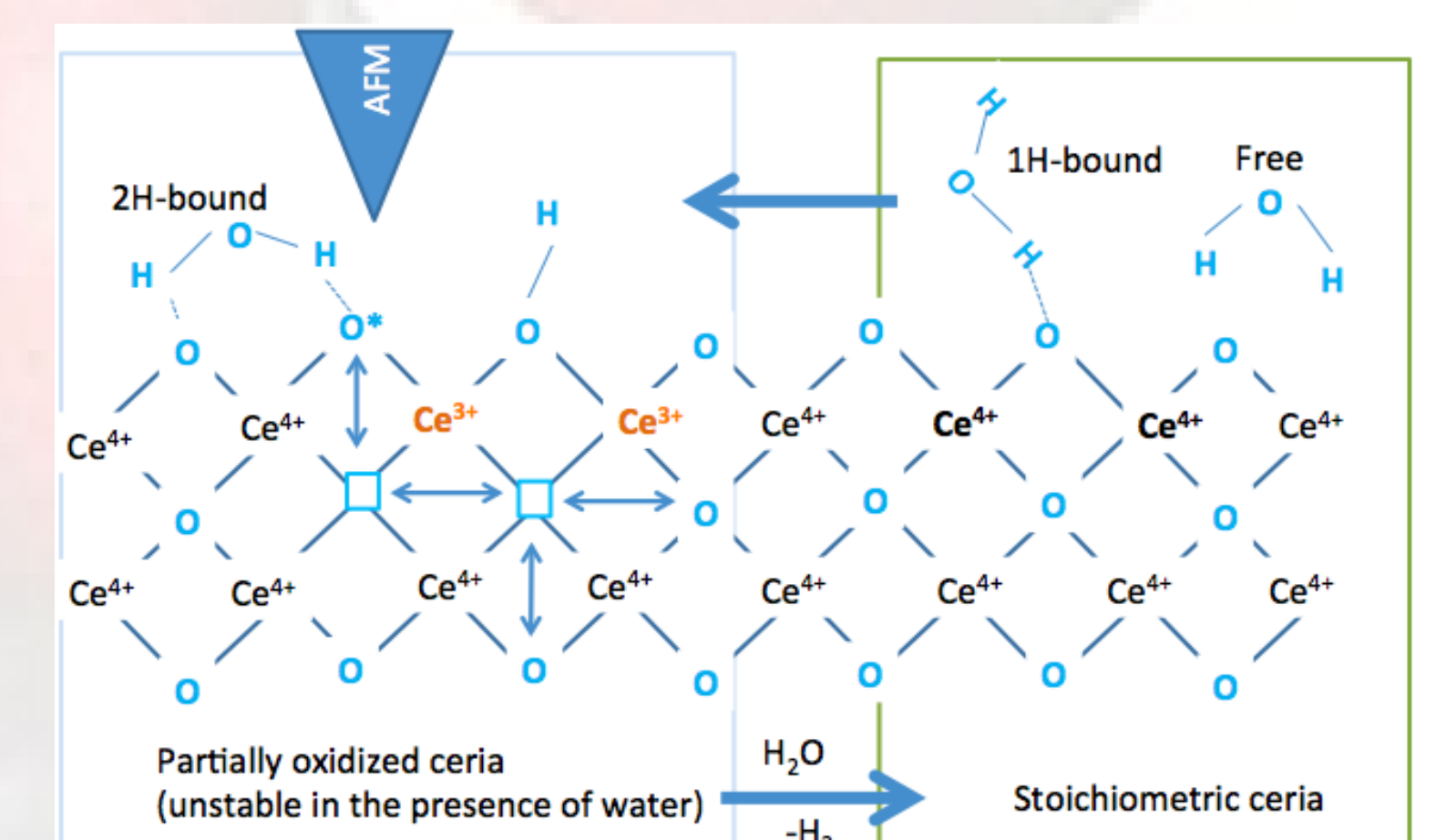


Fig 5: Unipolar first-order reversal curve (FORC) waveform. In this, the envelope of probe bias is an unipolar excitation waveform with increasing amplitude. The discrete behavior of the amplitude spectrogram clearly shows the irreversible nature of the current process, and the shift of the resonant frequency to higher values reveals the increase in the tip-sample contact stiffness, due to the stronger interactions during the nanowriting process.

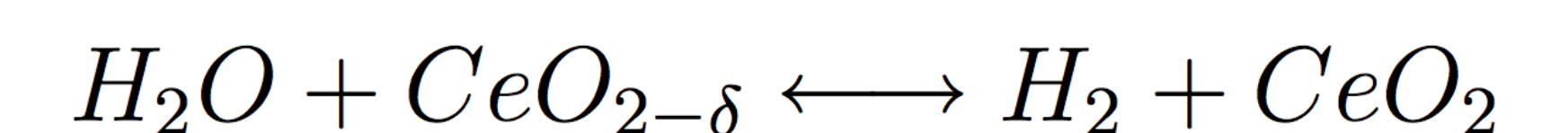
CONCLUSIONS



- Electrochemically driven oxygen vacancy formation. Energy requirement is about 2.87 eV:

$$E_v = E_{CeO_2 (reduced)} + \frac{1}{2}E_{O_2} - E_{CeO_2 (stoichiometric)}$$

- Electrochemically reduced ceria surface (oxygen defects) favors water physical adsorption in two forms (two H-bond structure and hydroxyl surface). Thermodynamically, both forms create favorable condition for water decomposition at low temperatures (<400°C) and low partial pressure of hydrogen:



REFERENCES

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[2] Balke et al., Adv. Mater. 2010, 22, E193-E209

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